

High-speed diode

P/b Lead(Pb)-Free

DESCRIPTION

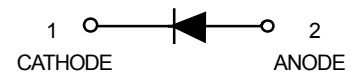
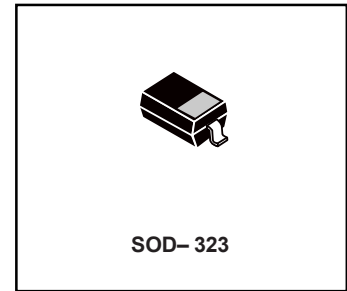
The BAS316 is a high-speed switching diode fabricated in planar technology, and encapsulated in the SOD323(SC76) SMD plastic package.

FEATURES

- Ultra small plastic SMD package
- High switching speed: max. 4 ns
- Continuous reverse voltage: max. 75 V
- Repetitive peak reverse voltage: max. 100 V
- Repetitive peak forward current: max. 500 mA.
- We declare that the material of product compliance with RoHS requirements.
- S- Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable.

APPLICATIONS

- High-speed switching in e.g. surface mounted circuits.



ORDERING INFORMATION

Device	Marking	Shipping
BAS316 S-BAS316	Z9	3000 Tape & Reel
BAS316 S-BAS316	Z9	10000 Tape & Reel

ELECTRICAL CHARACTERISTICS $T_j=25^{\circ}\text{C}$ unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MAX.	UNIT
V_F	forward voltage	see Fig.2 $I_F = 1 \text{ mA}$	715	mV
		$I_F = 10 \text{ mA}$	855	mV
		$I_F = 50 \text{ mA}$	1	V
		$I_F = 150 \text{ mA}$	1.25	V
I_R	reverse current	see Fig.4 $V_R = 25 \text{ V}$	30	nA
		$V_R = 75 \text{ V}$	1	μA
		$V_R = 25 \text{ V}; T_j = 150^{\circ}\text{C}$	30	μA
		$V_R = 75 \text{ V}; T_j = 150^{\circ}\text{C};$	50	μA
C_d	diode capacitance	$f = 1 \text{ MHz}; V_R = 0$; see Fig.5	2	pF
t_{rr}	reverse recovery time	when switched from $I_F = 10 \text{ mA}$ to $I_R = 10 \text{ mA}$; $R_L = 100\Omega$; measured at $I_R = 1 \text{ mA}$; see Fig.6	4	ns
V_{fr}	forward recovery voltage	when switched from $I_F = 10 \text{ mA}$; $t_r = 20 \text{ ns}$; see Fig.7	1.75	V

LIMITING VALUES In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{RRM}	repetitive peak reverse voltage		–	100	V
V_R	continuous reverse voltage		–	75	V
$V_{R(RMS)}$	RMS reverse voltage		–	53	V
I_F	continuous forward current		–	250	mA
I_{FRM}	repetitive peak forward current		–	500	mA
I_{FSM}	non-repetitive peak forward current	square wave; $T_j=25^\circ\text{C}$ prior to surge; see Fig.3			
		$t = 1\mu\text{s}$	–	5	A
		$t = 1\text{ ms}$	–	1	A
		$t = 1\text{ s}$	–	0.5	A
P_{tot}	total power dissipation		–	200	mW
$R_{\theta JA}$	thermal resistance junction to ambient air		–	625	$^\circ\text{C}/\text{W}$
T_{stg}	storage temperature		-55	+150	$^\circ\text{C}$
T_j	junction temperature		–	150	$^\circ\text{C}$

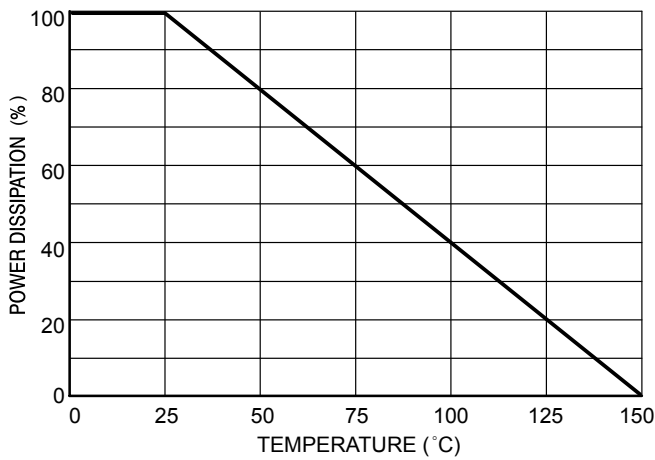


Fig.1 Steady State Power Derating

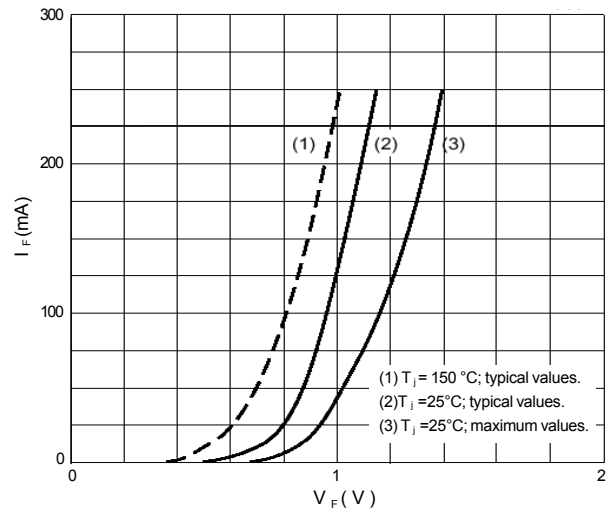


Fig.2 Forward current as a function of forward voltage.

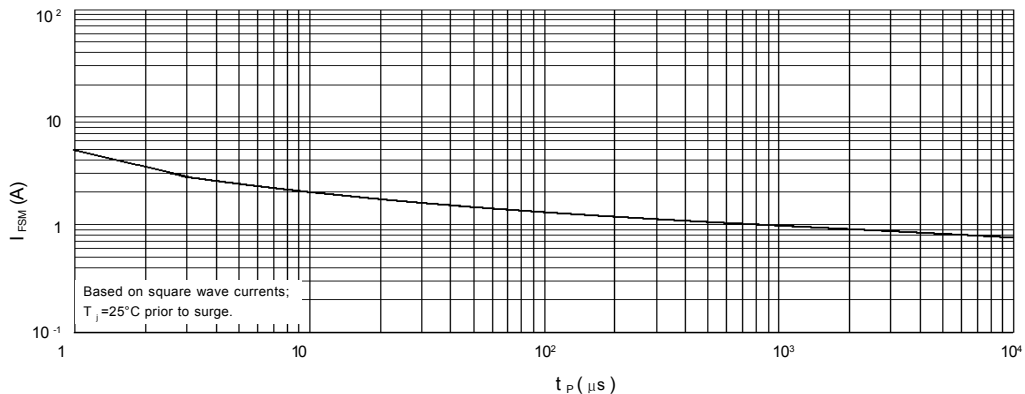


Fig.3 Maximum permissible non-repetitive peak forward current as a function of pulse duration.

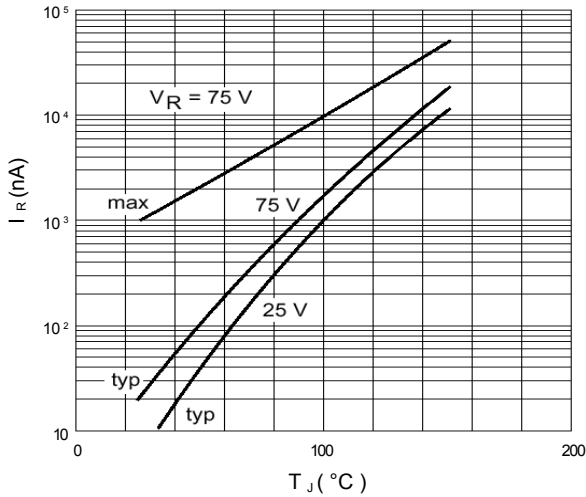


Fig.4 Reverse current as a function of junction temperature.

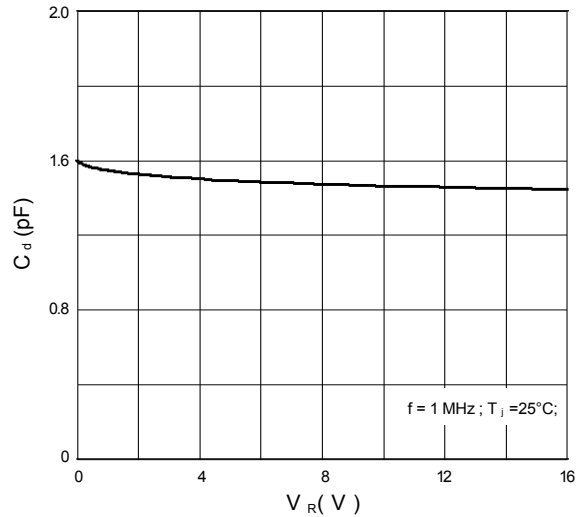
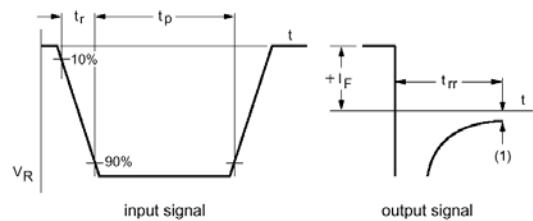
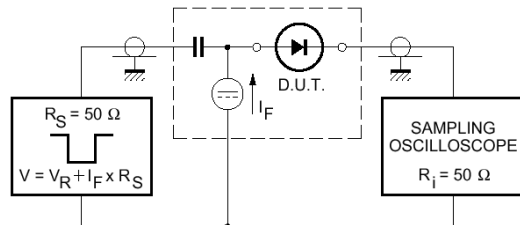
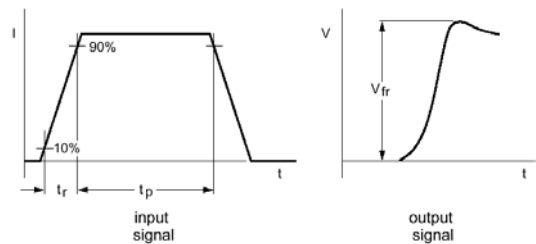
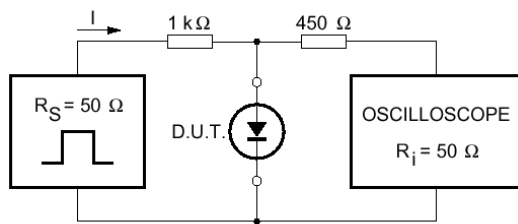


Fig.5 Diode capacitance as a function of reverse voltage; typical values.



(1) $I_R = 1 \text{ mA}$.
 Input signal: reverse pulse rise time $t_r = 0.6 \text{ ns}$; reverse voltage pulse duration $t_p = 100 \text{ ns}$; duty factor $\delta \approx 0.05$;
 Oscilloscope: rise time $t_r = 0.35 \text{ ns}$.

Fig.6 Reverse recovery voltage test circuit and waveforms.



Input signal: forward pulse rise time $t_r = 20 \text{ ns}$; forward current pulse duration $t_p \geq 100 \text{ ns}$; duty factor $\delta \leq 0.005$.

Fig.7 Forward recovery voltage test circuit and waveforms.